



WANSEMI
万芯半导体

WP8810EA

Enhancement Mode N-Channel Power MOSFET

TSSOP8/NMOS/20V/ $\pm 10V$ /0.7V/7A/15.5m Ω

Rev1.2

20V, 15.5mΩ, 7A, N-Channel MOSFET

1.Features

- ◆ 20V MOSFET technology
- ◆ Low on-state resistance
- ◆ Fast switching
- ◆ $V_{GS} \pm 10V$
- ◆ ESD Protected

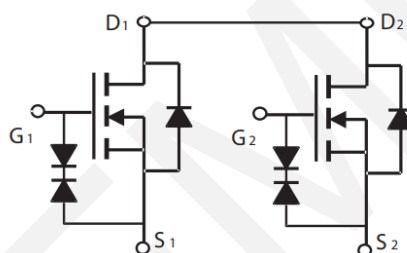
V_{DS}	$R_{DS(on)}$ Typ.	I_D Max.
20V	15.5mΩ @ 4.5V	7A
	19mΩ @ 2.5V	

2.Applications

- ◆ Power Switching Application
- ◆ Load Switching



TSSOP8
Pin Description



Schematic Diagram

3.Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP8810EA	8810E	TSSOP8	5,000	80,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V_{DSS}	20	V
Gate to Source Voltage	V_{GSS}	± 10	V
Drain Current (DC)	I_D	7	A
Drain Current (Pulse), $PW \leq 300\mu s$	I_{DP}	30	A
Total Dissipation	P_D	1.5	W
Junction Temperature	T_j	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

5. Thermal Resistance Ratings(Note 2)

Parameter	Symbol	Value	Unit
Junction to Ambient	$R_{\theta JA}$	85	$^{\circ}\text{C/W}$

Note 2: When mounted on 1 inch square copper board $t \leq 10\text{sec}$ The value in any given application depends on the user's specific board design.

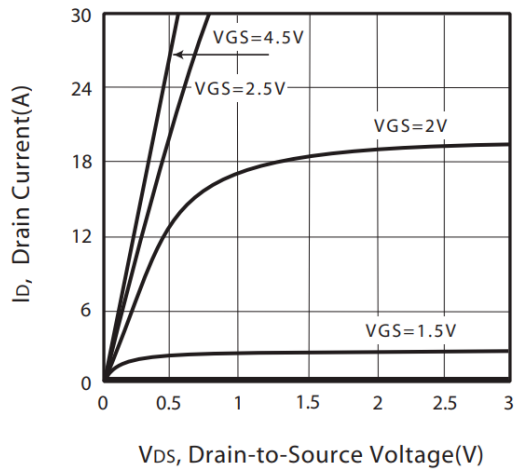
6. Electrical Characteristics at $T_a=25^{\circ}\text{C}$ (Note 3)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	20	-	-	V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 16\text{V}$, $V_{GS} = 0\text{V}$	-	-	1	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 10\text{V}$, $V_{SS} = 0\text{V}$	-	-	± 10	μA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{DS}=250\mu\text{A}$	0.5	0.7	1.0	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 7\text{A}$, $V_{GS} = 4.5\text{V}$	-	15.5	20	$\text{m}\Omega$
		$I_D = 5.5\text{A}$, $V_{GS} = 2.5\text{V}$	-	19	24	$\text{m}\Omega$
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}$, $V_{DS}=10\text{V}$, Frequency=1.0MHz	-	815	-	pF
Output Capacitance	C_{oss}		-	215	-	pF
Reverse Transfer Capacitance	C_{rss}		-	180	-	pF
Turn-ON Delay Time	$t_{d(on)}$	$V_{DD} = 10\text{V}$, $I_D = 1\text{A}$, $V_{GS} = 4.5\text{V}$, $R_G = 10\Omega$	-	28	-	ns
Rise Time	t_r		-	83	-	ns
Turn-OFF Delay Time	$t_{d(off)}$		-	63	-	ns
Fall Time	t_f		-	41	-	ns
Total Gate Charge	Q_g	$V_{DS} = 10\text{V}$, $V_{GS} = 4.5\text{V}$, $I_D = 7\text{A}$	-	11.5	-	nC
	Q_{gs}		-	2.4	-	nC
	Q_{gd}		-	5	-	nC
Diode Forward Voltage	V_{FSD}	$I_S = 1\text{A}$, $V_{GS} = 0\text{V}$	-	0.8	1.2	V

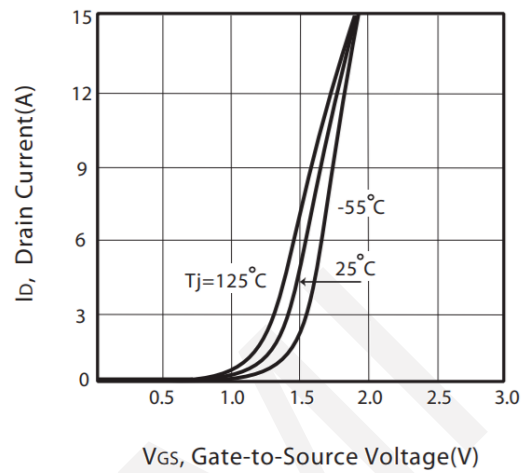
Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



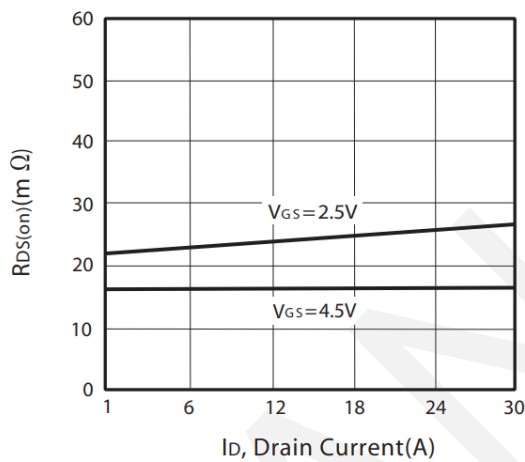
7. Typical electrical and thermal characteristics



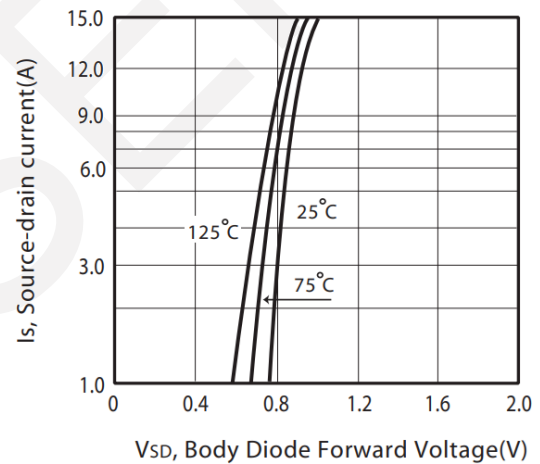
Output Characteristics



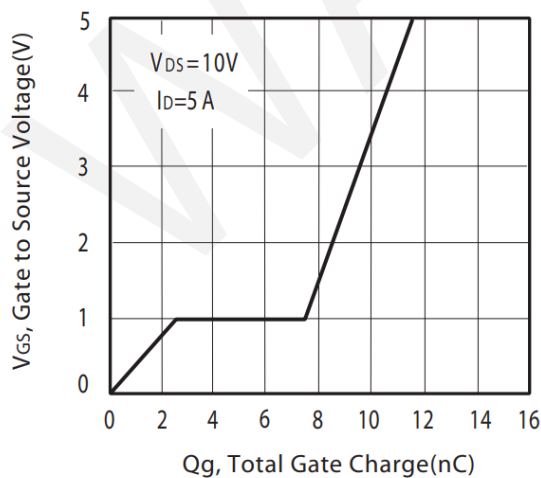
Typical Transfer Characteristics



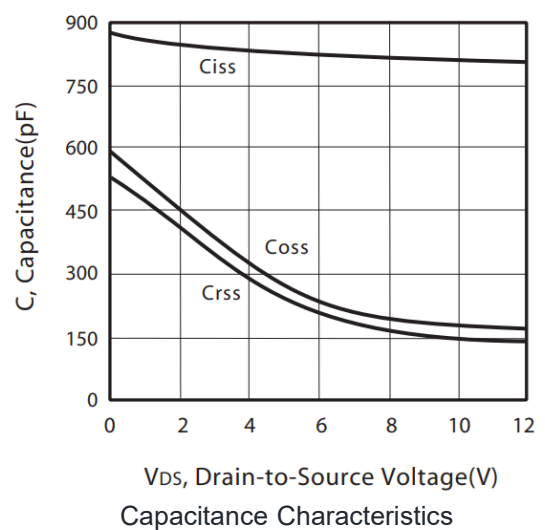
On-resistance vs. Drain Current

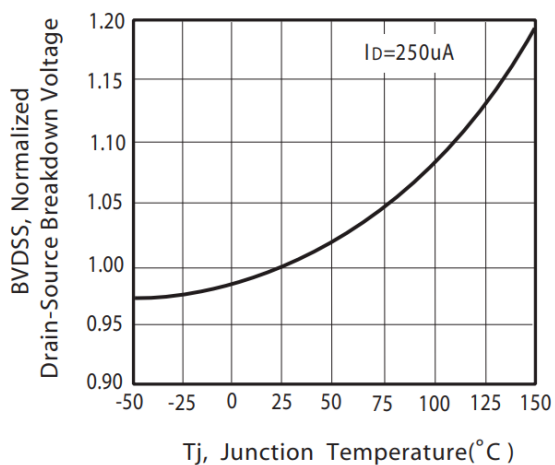


Body Diode Characteristics

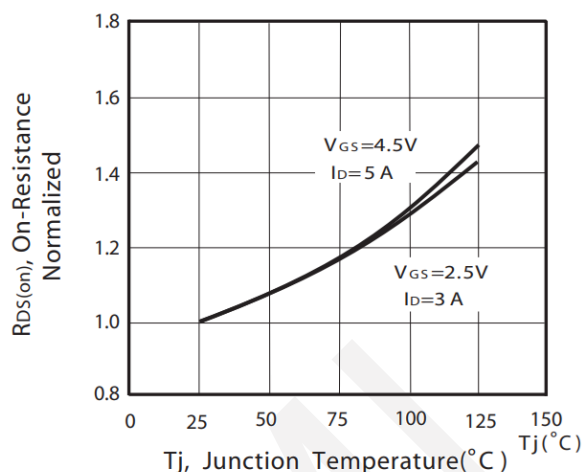


Gate Charge Characteristics

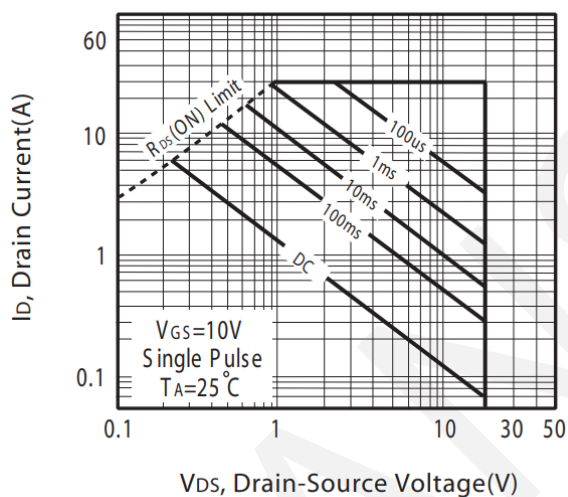




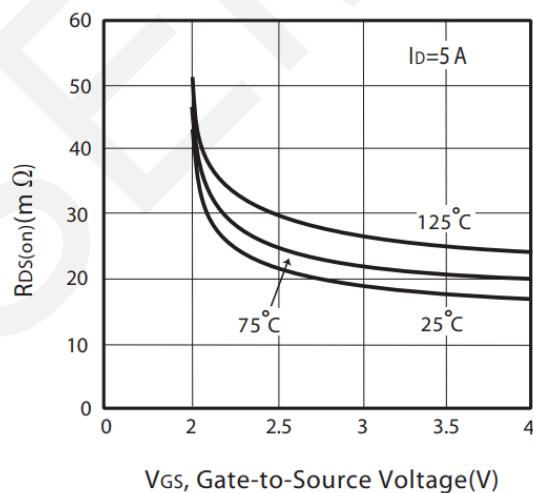
Normalized Breakdown Voltage vs.
Junction Temperature



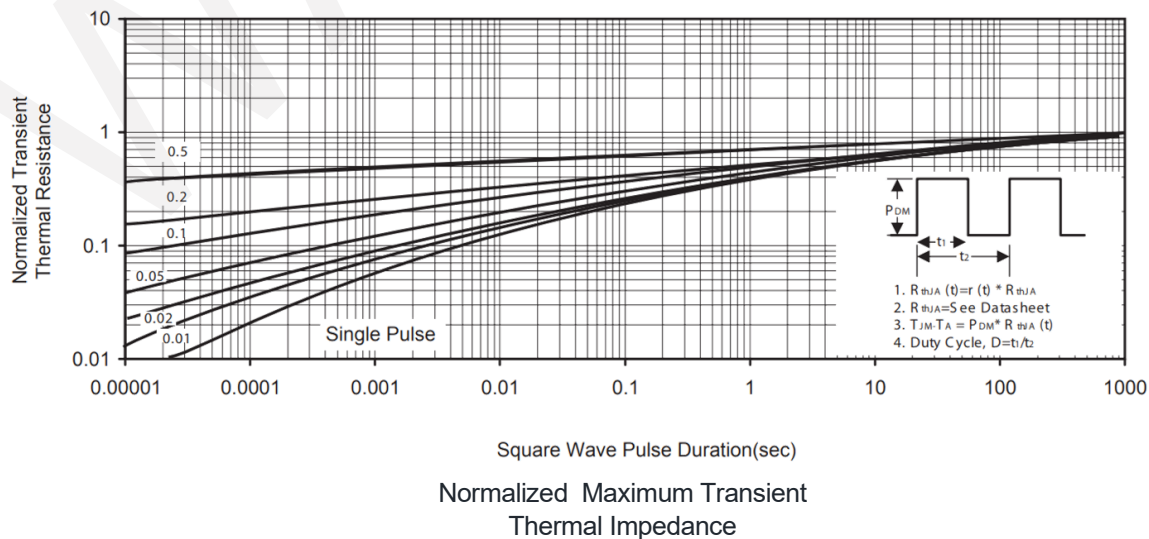
Normalized on Resistance vs.
Junction Temperature



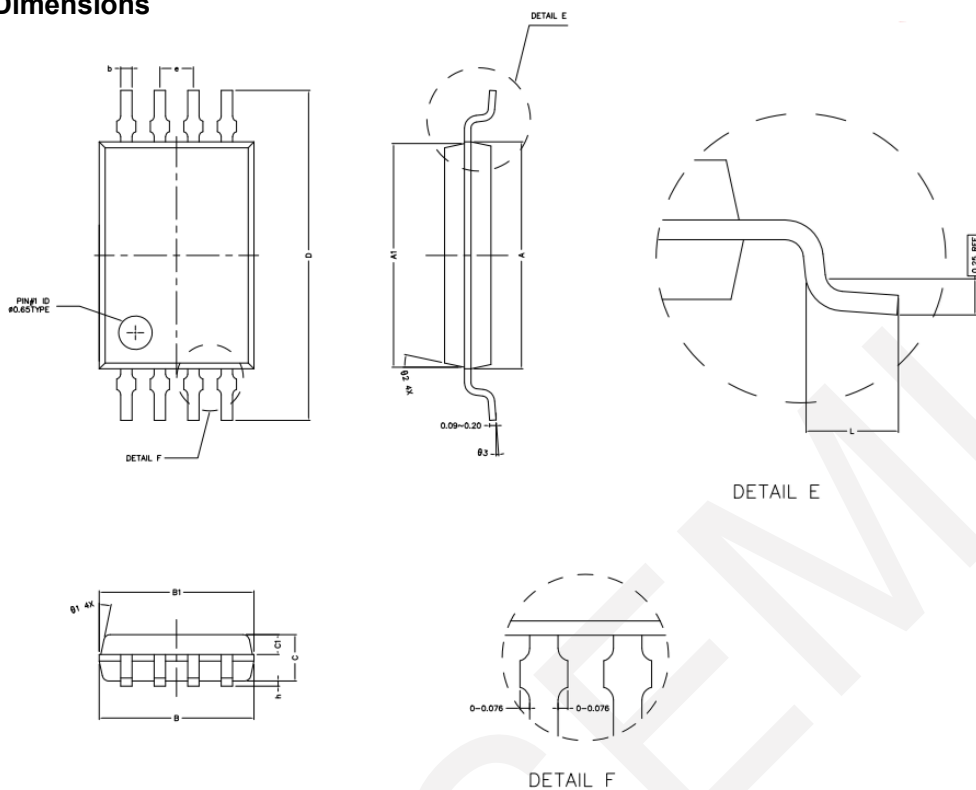
Maximum Safe Operating Area



On-Resistance vs. Gate-Source Voltage



8.Package Dimensions



COMMON DIMENSIONS (UNITS OF MEASURE IS mm)			
	MIN	NORMAL	MAX
A	4.300	4.400	4.500
A1	4.240	4.340	4.440
B	3.050	3.150	3.250
B1	2.840	2.940	3.040
C	0.850	0.900	0.950
C1	0.337	0.387	0.437
D	6.250	6.400	6.550
L	0.450	0.600	0.750
b	0.170	0.220	0.300
h	0.050	0.100	0.150
e	0.650TYPE		
θ_1	12° TYPE		
θ_2	12° TYPE		
θ_3	0° ~ 7°		

9. Important Notice

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